

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			09/911,320	MITTS ET AL.	
			Examiner	Art Unit	Page 1 of 1
			BRIAN P. YENKE	2614	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,816,201	11-2004	Fang et al.	348/468
X	B	US-6,766,528	07-2004	Kim et al.	725/113
X	C	US-6,766,163	07-2004	Sharma, Dipanshu	455/412.1
X	D	US-6,775,842	08-2004	Van Gestel, Henricus Antonius Wilhelmus	725/136
X	E	US-6,742,188	05-2004	Del Castillo, Leonardo	725/153
X	F	US-2004/0080528	04-2004	Rand et al.	345/738
X	G	US-2003/0212997	11-2003	Hejna, Donald J. JR.	725/88
X	H	US-2001/0049826	12-2001	Wilf, Itzhak	725/120
X	I	US-6,243,676	06-2001	Witteman, Bradley James	704/243
X	J	US-5,703,655	12-1997	Corey et al.	348/468
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.